


<b>Search Notes</b> 	<b>Application/Control No.</b> 10087409	<b>Applicant(s)/Patent Under Reexamination</b> MOGHADDAM, BABACK
	<b>Examiner</b> SHEELA C CHAWAN	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	115,124,125,173,181,190,192,266,254,272,270,289,276,286,195,301,228,206,274-275,296,395,276,224,260	2/20/11	SCC
340	5.82,5.83	2/20/11	SCC
356	71	2/20/11	SCC
705	53	2/20/11	SCC
382	124, 125, 190, 254	2/20/11	SCC
356	71	2/20/11	SCC
SEARCH UP-DATE		2/20/11	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	2/20/11	SCC
SEARCH INVENTOR NAME	2/20/11	SCC
(382/124,125,115,254,173,289,209,116,266,272,126,127,195,296,260,274,190,192,228,154.ccls.)	2/20/11	SCC
340/5.82,5.83.CCLS.	2/20/11	SCC
356/71.CCLS.	2/20/11	SCC
348/E5.008,E7.06,E7.009,E7.024,E5.006,E7.07.CCLS.	2/20/11	SCC
375/E5.008,E7.06,E7.009,E7.024.CCLS.	2/20/11	SCC
GOGGLE SEARCH.	2/20/11	SCC
SEARCH IEEE OR INSPEC DATA BASE.	2/20/11	SCC
SEARCH UP-DATE	2/20/11	SCC
INTERFERENCE SEARCH.	2/20/11	SCC
summing weights threshold (less or more) score   similarity test image   reference image fingerprint OR finger OR minutiae feature extraction filetype:pdf GOGGLE SEARCH.		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	124, 125, 190, 254	2/20/11	SCC
356	71	2/20/11	SCC

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INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
INTERFERE NCE SEARCH.		2/20/11	SCC